

OptiMOS(TM)3 Power-Transistor

Features

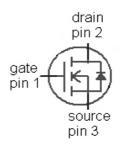
- Ideal for high frequency switching and sync. rec.
- Optimized technology for DC/DC converters
- Excellent gate charge x R DS(on) product (FOM)
- Very low on-resistance R_{DS(on)}
- N-channel, normal level
- 100% avalanche tested
- Pb-free plating; RoHS compliant
- Qualified according to JEDEC¹⁾ for target applications

Туре	IPD088N06N3 G
	2 (tab)
Package	PG-TO252-3
Marking	088N06N

Product Summary

V _{DS}	60	٧
R _{DS(on),max}	8.8	mΩ
I _D	50	Α





Maximum ratings, at T_j =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	I _D	T _C =25 °C ²⁾	50	А
		T _C =100 °C	47	
Pulsed drain current ³⁾	I _{D,pulse}	T _C =25 °C	200	
Avalanche energy, single pulse ⁴⁾	E _{AS}	$I_{\rm D}$ =50 A, $R_{\rm GS}$ =25 Ω	43	mJ
Gate source voltage	V_{GS}		±20	V
Power dissipation	P _{tot}	T _C =25 °C	71	W
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$		-55 175	°C
IEC climatic category; DIN IEC 68-1			55/175/56	

¹⁾J-STD20 and JESD22

 $^{^{2)}}$ Current is limited by bondwire; with an R_{thJC} =2.1 K/W the chip is able to carry 67 A.

³⁾ See figure 3 for more detailed information

⁴⁾ See figure 13 for more detailed information



Parameter	Symbol	Conditions	Values		Unit	
			min.	typ.	max.	
Thermal characteristics						
Thermal resistance, junction - case	R _{thJC}		-	-	2.1	K/W
Thermal resistance,	R_{thJA}	minimal footprint	-	-	62	
junction - ambient		6 cm² cooling area ⁴⁾	-	-	40	

Electrical characteristics, at T_j =25 °C, unless otherwise specified

Static characteristics

Drain-source breakdown voltage	V _{(BR)DSS}	V _{GS} =0 V, I _D =1 mA	60	-	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	V _{DS} =V _{GS} , I _D =34 μA	2	3	4	
Zero gate voltage drain current	I _{DSS}	V _{DS} =60 V, V _{GS} =0 V, T _j =25 °C	1	0.1	1	μΑ
		V _{DS} =60 V, V _{GS} =0 V, T _j =125 °C	1	10	100	
Gate-source leakage current	I _{GSS}	V _{GS} =20 V, V _{DS} =0 V	-	1	100	nA
Drain-source on-state resistance	R _{DS(on)}	V _{GS} =10 V, I _D =50 A	-	7.1	8.8	mΩ
Gate resistance	R _G		-	0.9	-	Ω
Transconductance	g fs	V _{DS} >2 I _D R _{DS(on)max} , I _D =50 A	29	57	- 1	s

 $^{^{4)}}$ Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm² (one layer, 70 μ m thick) copper area for drain connection. PCB is vertical in still air.



Parameter	Symbol Conditions		Values			Unit
			min.	typ.	max.	
Dynamic characteristics						
Input capacitance	C iss		-	2900	3900	pF
Output capacitance	C _{oss}	V_{GS} =0 V, V_{DS} =30 V, f=1 MHz	-	640	850]
Reverse transfer capacitance	C _{rss}		-	23	-	
Turn-on delay time	t _{d(on)}		-	15	-	ns
Rise time	t _r	V _{DD} =30 V, V _{GS} =10 V,	-	40	-	
Turn-off delay time	$t_{d(off)}$	$I_{\rm D}$ =45 A, $R_{\rm G}$ =3.5 Ω	-	20	-	
Fall time	t _f		-	5	-	
Gate Charge Characteristics ⁵⁾		,				
Gate to source charge	Q _{gs}		-	16	-	nC
Gate to drain charge	Q _{gd}	1, 20,4, 50,4	-	3	-	
Switching charge	Q_{sw}	V _{DD} =30 V, / _D =50 A, V _{GS} =0 to 10 V	-	11	-	
Gate charge total	Q _g		ı	36	48	
Gate plateau voltage	V _{plateau}		ı	5.6	1	٧
Output charge	Q _{oss}	V _{DD} =30 V, V _{GS} =0 V	-	29	38	nC
Reverse Diode						
Diode continous forward current	Is	T -25 °C	-	-	50	А
Diode pulse current	/ _{S,pulse}	T _C =25 °C	-	-	200	
Diode forward voltage	V _{SD}	V _{GS} =0 V, I _F =50 A, T _j =25 °C	-	1.0	1.2	V
Reverse recovery time	t _{rr}	V _R =30 V, I _F =45A,	_	45	-	ns
Reverse recovery charge	Q _{rr}	d <i>i</i> _F /d <i>t</i> =100 A/μs	-	40	-	nC

 $^{^{5)}\,\}mathrm{See}$ figure 16 for gate charge parameter definition

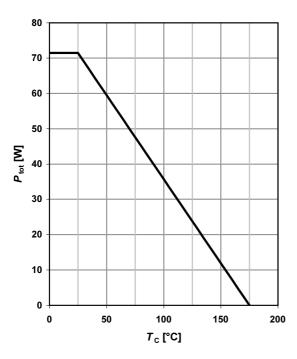


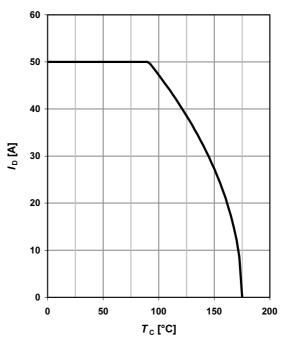
1 Power dissipation

P_{tot} =f(T_{C})

2 Drain current

$$I_D = f(T_C); V_{GS} \ge 10 \text{ V}$$





3 Safe operating area

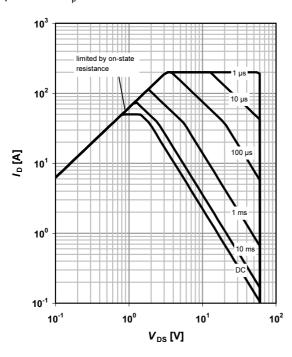
$$I_D$$
=f(V_{DS}); T_C =25 °C; D =0

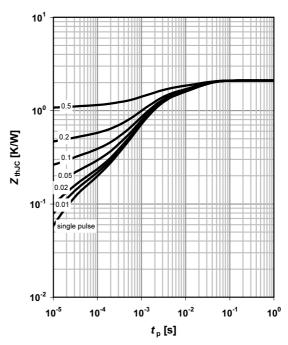
parameter: t_p

4 Max. transient thermal impedance

$$Z_{thJC}$$
=f(t_p)

parameter: $D = t_p/T$



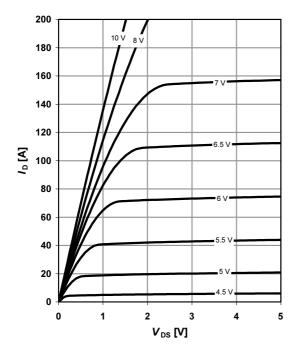




5 Typ. output characteristics

 $I_D=f(V_{DS}); T_j=25 \text{ °C}$

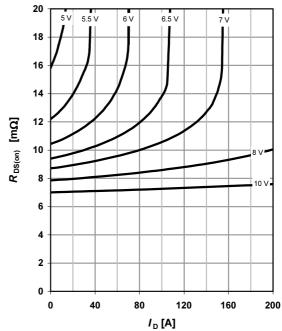
parameter: V_{GS}



6 Typ. drain-source on resistance

 $R_{DS(on)}$ =f(I_D); T_j =25 °C

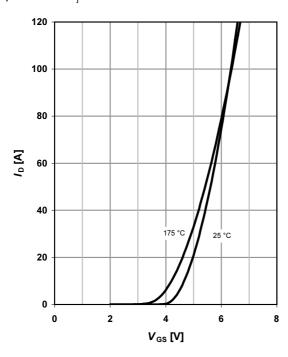
parameter: V_{GS}



7 Typ. transfer characteristics

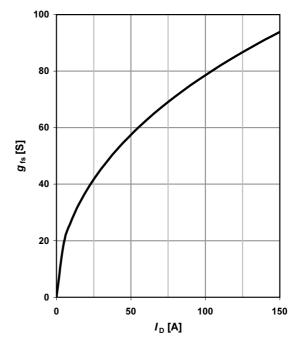
 $I_D = f(V_{GS}); |V_{DS}| > 2|I_D|R_{DS(on)max}$

parameter: T_j



8 Typ. forward transconductance

 g_{fs} =f(I_D); T_j =25 °C





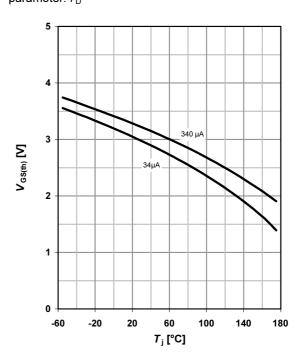
9 Drain-source on-state resistance

 $R_{DS(on)}$ =f(T_j); I_D =50 A; V_{GS} =10 V

20 18 16 14 R_{DS(on)} [mΩ] 12 10 6 4 2 0 20 -60 -20 140 180 *T*_j [°C]

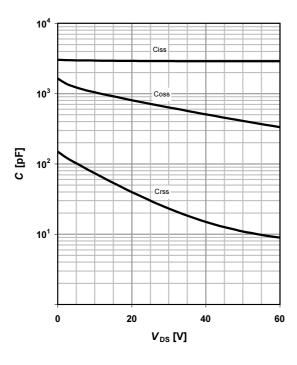
10 Typ. gate threshold voltage

 $V_{\rm GS(th)}$ =f($T_{\rm j}$); $V_{\rm GS}$ = $V_{\rm DS}$ parameter: $I_{\rm D}$



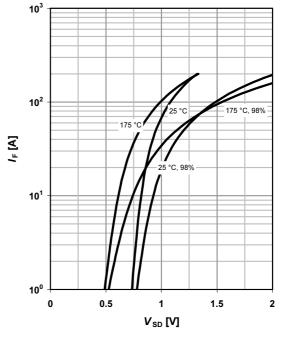
11 Typ. capacitances

 $C = f(V_{DS}); V_{GS} = 0 V; f = 1 MHz$



12 Forward characteristics of reverse diode

 I_{F} =f(V_{SD})
parameter: T_{j}





13 Avalanche characteristics

 I_{AS} =f(t_{AV}); R_{GS} =25 Ω

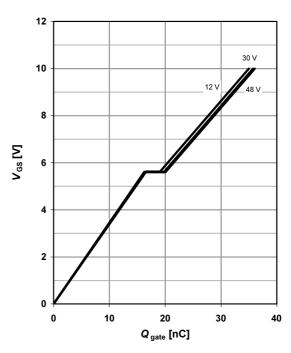
parameter: $T_{\rm j(start)}$

100 150 °C 100 °C 25 °C 100 °C 25 °C 100 °C 100 °C 100 °C 25 °C 100 °C 100

14 Typ. gate charge

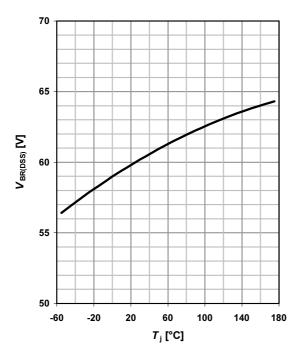
 $V_{\rm GS}$ =f(Q_{gate}); $I_{\rm D}$ =50 A pulsed

parameter: $V_{\rm DD}$

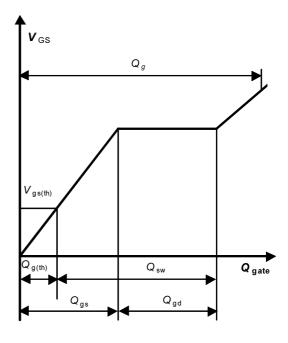


15 Drain-source breakdown voltage

 $V_{BR(DSS)}$ =f(T_j); I_D =1 mA

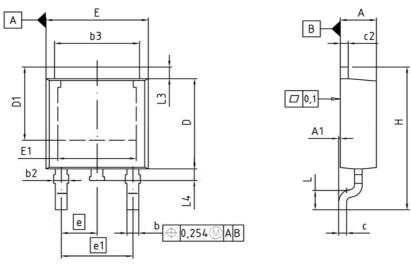


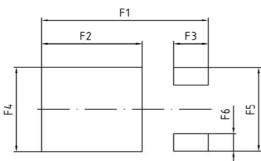
16 Gate charge waveforms



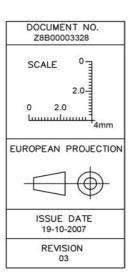


PG-TO252 (D-Pak)





DIM	MILLIN	METERS	INC	HES	
DIM	MIN	MAX	MIN	MAX	
Α	2.16	2.41	0.085	0.095	
A1	0.00	0.15	0.000	0.006	
Ь	0.64	0.89	0.025	0.035	
b2	0.65	1.15	0.026	0.045	
ь3	5.00	5.50	0.197	0.217	
С	0.46	0.60	0.018	0.024	
c2	0.46	0.98	0.018	0.039	
D	5.97	6.22	0.235	0.245	
D1	5.02	5.84	0.198	0.230	
E	6.40	6.73	0.252	0.265	
E1	4.70	5.21	0.185	0.205	
е	2	2.29	0.090		
e1	4	4.57		0.180	
N		3	3		
Н	9.40	10.48	0.370	0.413	
L	1.18	1.70	0.046	0.067	
L3	0.90	1.25	0.035	0.049	
L4	0.51	1.00	0.020	0.039	
F1	10.50	10.70	0.413	0.421	
F2	6.30	6.50	0.248	0.256	
F3	2.10	2.30	0.083	0.091	
F4	5.70	5.90	0.224	0.232	
F5	5.66	5.86	0.223	0.231	
F6	1.10	1.30	0.043	0.051	





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